<b>PCN Number:</b> 20170915005	PCN Date:	Sept	ember 20, 2017				
Title: Datasheet for bq25600, bq25600D							
Customer Contact: PCN Manager		De	pt: Quality Services				
Change Type:							
	Design		Wafer Bump Site				
	Data Sheet	H	Wafer Bump Material				
	Part number change	Π	Wafer Bump Process				
	est Site		Wafer Fab Site				
	Test Process		Wafer Fab Materials				
			Wafer Fab Process				
Notification Details							
Description of Change:							
Texas Instruments Incorporated is announcing an information only notification.							
The product datasheet(s) is being update							
The following change history provides fu	rther details.						
TEXAS INSTRUMENTS			bq25600, bq25600D				
INSTROMENTS	ę	SLUSC	J4A - JUNE 2017-REVISED AUGUST 2017				
			CAL METERS				
Changes from Original (June 2017) to Revision A			Page				
Updated data sheet title							
Deleted 200 nS Fast Turn-Off in Features			1				
Updated Simplified Application schematic			1				
Changed ACDRV pin references to "NC" in Pin Co							
Deleted ACDRV pin references from Pin Function	s table		4				
Updated VAC pin description in Pin Functions tab	le						
Deleted ACDRV pin references from Absolute Maximum Ratings table							
	Added ESD Ratings table						
Added Input supply current specification (IVACVBUS_							
Deleted VAC debounce time (I <sub>DEB</sub> ) specification free	om Timing Requirements						
Updated Functional Block Diagram 16							
Updated Power Up from Input Source section							
Deleted Power Up OVPFET section							
Deleted OVPFET Startup Control timing illustration							
Updated Input Overvoltage (ACOV) section							
Updated Power Path Management Application schematic							
Updated bq25600D Applications Diagram schematic							
The datasheet number will be changing.							
Device Family	Change From:		Change To:				
bq25600, bq25600D	SLUSCJ4		SLUSCJ4A				
These changes may be reviewed at the datasheet links provided.							
http://www.ti.com/product/BQ25600							
Reason for Change:							
bq25600 and bq25600D will not support external OVP (Over Voltage Protection) FET							
configuration.							
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):							
The bq25600 and bq25600D were specified for 2 applications to support or not support external							

OVP FET. The customer impact is: External OVP FET is no longer supported by the device. There will be no impact to customer designs without external OVP FET. Changes to product identification resulting from this PCN:

Texas Instruments Incorporated

None.					
Product Affected:					
BQ25600DYFFR	BQ25600DYFFT	BQ25600YFFR	BQ25600YFFT		

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail	
USA	PCNAmericasContact@list.ti.com	
Europe	PCNEuropeContact@list.ti.com	
Asia Pacific	PCNAsiaContact@list.ti.com	
Japan	PCNJapanContact@list.ti.com	